

<b>Notice of References Cited</b>	Application/Control No. 10/615,080	Applicant(s)/Patent Under Reexamination KOSTER, KARL	
	Examiner Chuck Huynh	Art Unit 2683	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0148771	08-2003	de Verteuil, Andre Laurent	455/456
	B	US-5,758,288	05-1998	Dunn et al.	455/456.5
	C	US-5,727,057	03-1998	Emery et al.	379/201.07
	D	US-6,424,840	07-2002	Fitch et al.	455/456.1
	E	US-6,675,012	01-2004	Gray, Steven D.	455/423
	F	US-6,704,563	03-2004	Senn et al.	455/406
	G	US-6,404,388	06-2002	Sollenberger et al.	342/387
	H	US-6,456,839	09-2002	Chow et al.	455/408
	I	US-6,023,617	02-2000	Cooper et al.	455/403
	J	US-6,324,404	11-2001	Dennison et al.	455/456.1
	K	US-6,026,290	02-2000	Lamkin et al.	455/405
	L	US-6,073,012	06-2000	Vanden Heuvel et al.	455/427
	M	US-2002/0151305	10-2002	Ward et al.	455/436

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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